

Search Notes

Application/Control No.

10/791,669

Examiner

John P. Sheehan

Applicant(s)/Patent under
Reexamination

SHIRAISHI ET AL.

Art Unit

1742

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	3/21/2007	JPS